

Secondary Ion Mass Spectrometry – less  
conventional applications: TOF-SIMS,  
molecules and surfaces  
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Images in colour

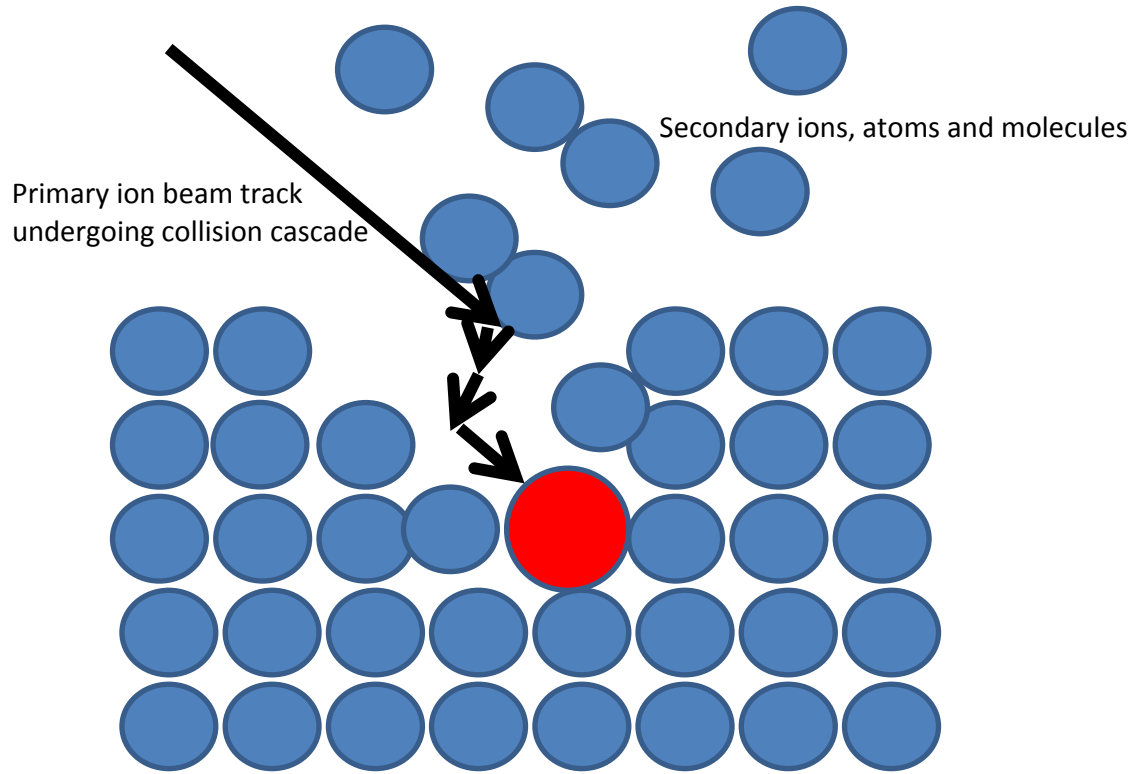


Fig. 1

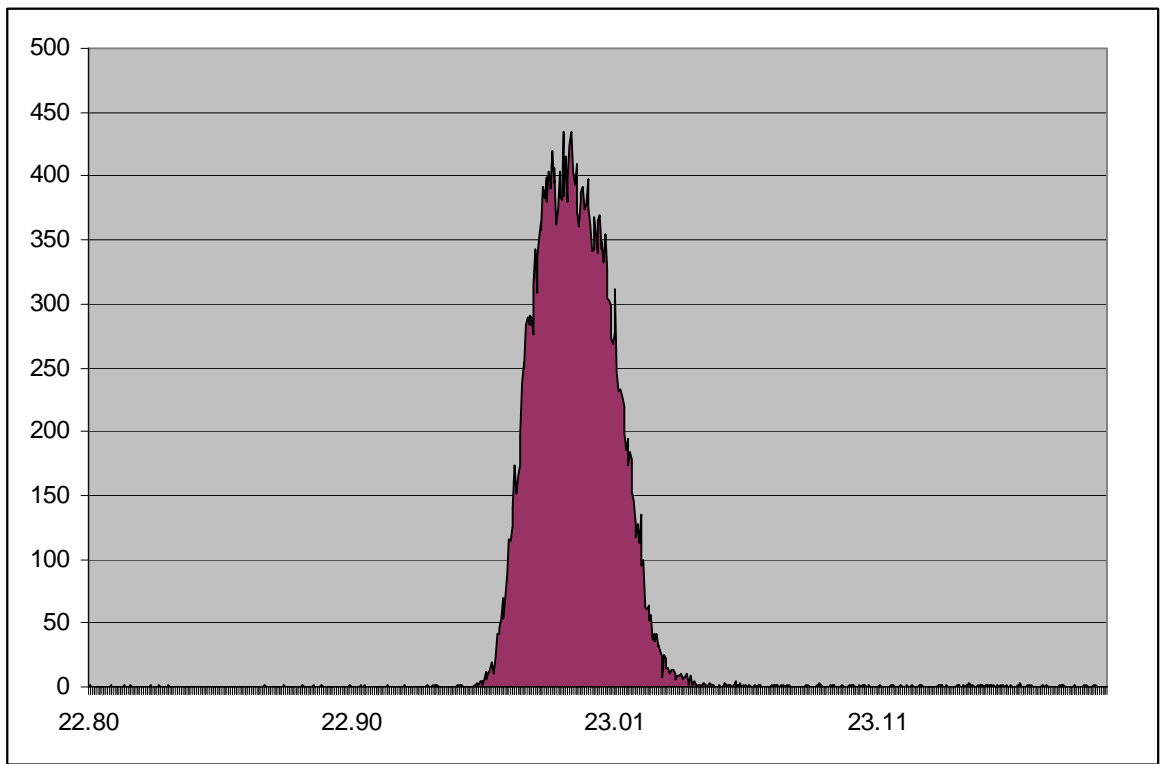


Fig. 6

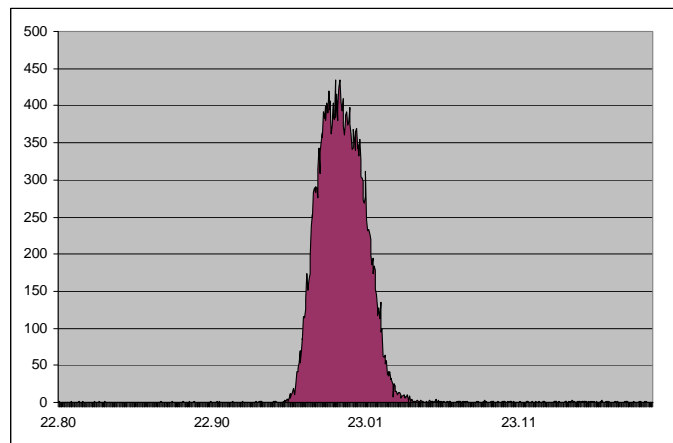


Fig. 7

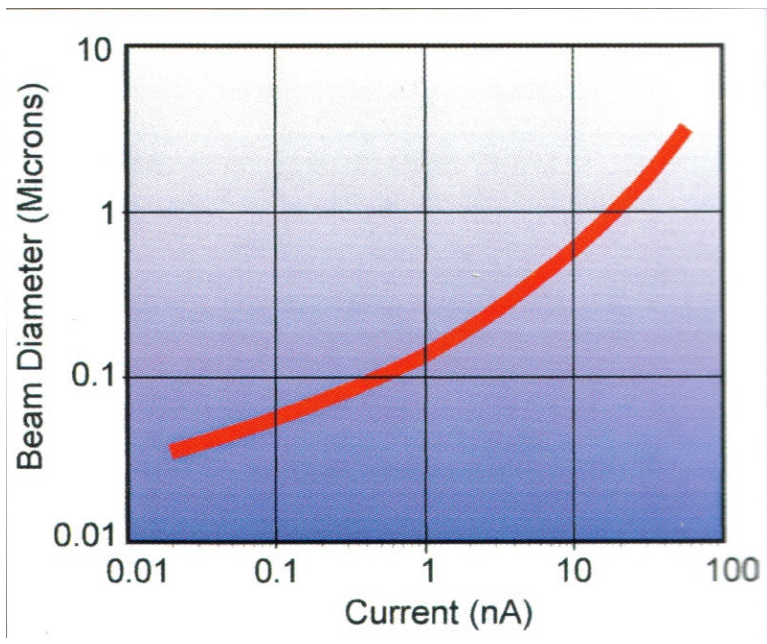


Fig 8